

## WP6: PROCESS AND PLATFORM INTEGRATION

**Leader:** ams AG – Jörg Siegert

**Start:** M9

**End:** M40



## Planned Efforts after updated DoW

Work package		AMS	VEEM	Crocus	FHG	TUW	UNIFE	AT	MASER	BESI	CEA	UNIPI	Total
WP6	Planned person.months per participant	22.0	13.0	2.0	3.0	3.0				10.0	3.0		56.0
	Actuals	31.7	13.0	2.8	3.0	3.5				10.1	1.0		65.1

## Deliverables

- D6.1: M12 ✓ Report on 3D integration concepts [AMS]
- D6.2: M29 ✓ Report on Manufacturing technology flow for WLP [BESI]
- D6.3: M27 ✓ Report on HVCMOS interposer manufacturing technology flow [AMS]
- D6.4: M40 ✓ Report on Evaluation of costs and manufacturability of the ATHENIS\_3D technology platform [AMS]
- D6.5: M27 ✓ Specification and commitment done for type of Demo Car [VES]

## Milestone

- MS4 M18 ✓ Specification and commitment done for type of Demo Car [VES]

### Overview:

- Define integration concepts for the AMS HVCMOS interposer with Cu TSV, Power Cu RDL, CROCUS eNVM MRAM and IPDs

### Challenges:

- Extreme requirements for very low On-resistance  $R_{on}$  for the H-bridge driver application → thick metallization ( $\geq 150 \mu\text{m}$ ) required → use DBC on ceramic substrate
- Wide range of operating requirements (e.g. high/low current, high/low density of interconnects, ...) → evaluate components

### Highlights:

- 3D integration concepts worked out together with partners and summarized in D661

## Overview:

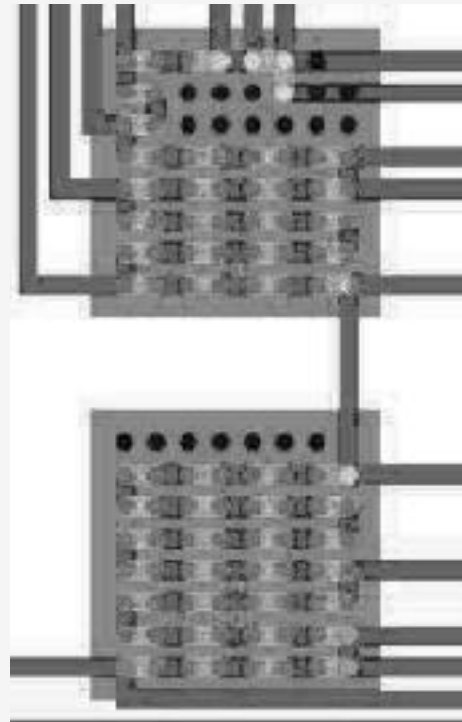
- Evaluation of suitable D2W stacking approaches suitable for applications in harsh environments

## Challenges:

- Pushing solder ball pitch beyond state-of-the art
- Low yield of samples after balling

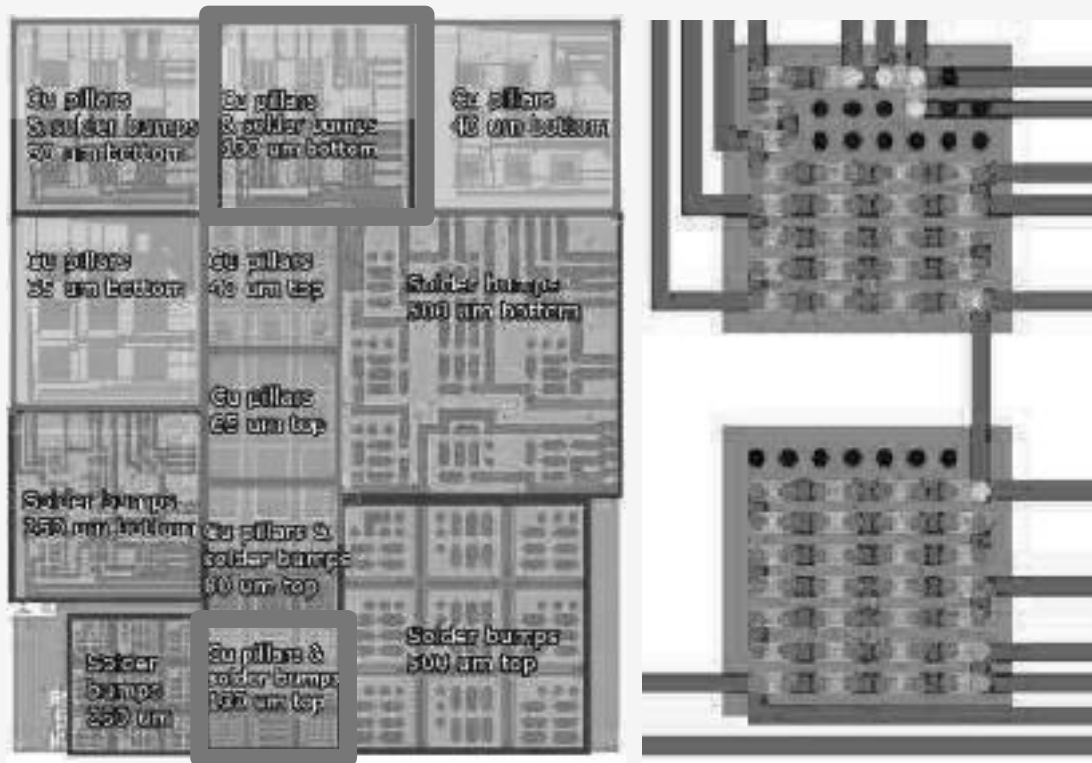
## Highlights:

- Manufacturing and successful electrical characterization (incl. reliability tests)
- D2W stacking of samples with 20  $\mu\text{m}$  bump/40  $\mu\text{m}$  pitch



Test vehicle	Bump type	Bump diameter	Bump pitch	Stacking process	Purpose
TV 1	Cu-pillars	20µm	40µm	TCB	Evaluate TCB process
				C2	Pushing the pitch limits beyond state-of-the-art
TV 2	Cu-pillars	30µm	65µm	C2	Evaluate C2 process
				TCB	TCB and C2 process comparison
TV 3	Cu-pillars	40µm	80µm	C2	Comparison w/ TV 2
	Solder balls			C4	Pushing the pitch limits beyond state-of-the-art
TV 4	Cu-pillars	70µm	130µm	C2	Comparison w/ TV 2 and TV 3
	Solder balls			C4	TV 4 – C2 and C4 process comparison

# D2W stacking – technology demonstrator



SoC: 165  $\mu\text{m}$  pad pitch / 75  $\mu\text{m}$  balls

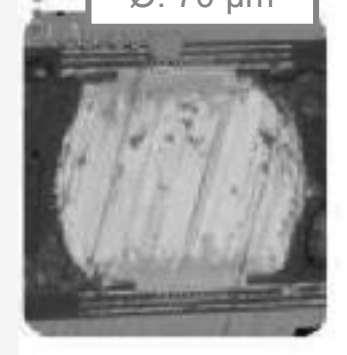
TV4: 130  $\mu\text{m}$  pad pitch / 70  $\mu\text{m}$  balls (4.35 x 4.35 mm<sup>2</sup>, 567 balls)

- Processed
  - Targeted interconnection with smallest diameter
    - Keep chip size small
    - Push limits of reflow process
  - Solder ball
    - Diameter: 40 & 70  $\mu\text{m}$
  - Copper pillar
    - Diameter: 20 & 30  $\mu\text{m}$
- Characterization done on all processed interconnections
- First reliability test done on solder balls with diameters of 70  $\mu\text{m}$

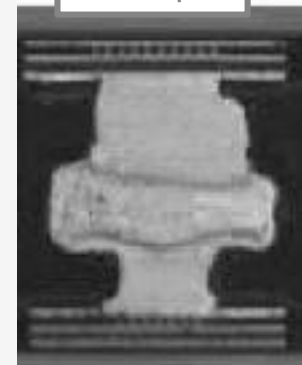
Solder balls  
 $\text{\O}: 40 \mu\text{m}$



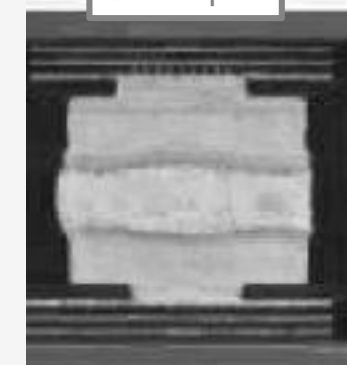
Solder balls  
 $\text{\O}: 70 \mu\text{m}$



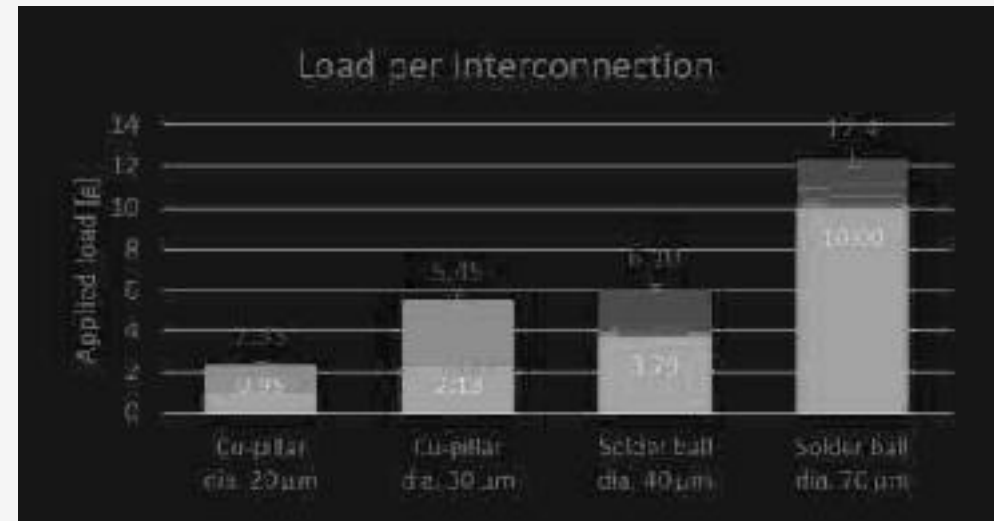
Cu pillar  
 $\text{\O}: 20 \mu\text{m}$



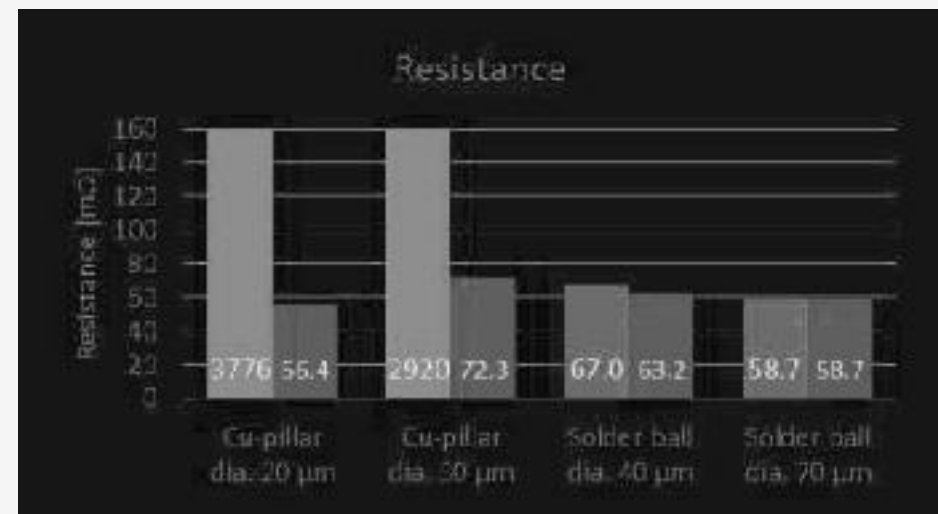
Cu pillar  
 $\text{\O}: 30 \mu\text{m}$



- Mechanical characterization
  - Shear test
  - Minimum load values according to BESI standard
  - Stability increase with interconnect size



- Electrical characterization
  - Resistance of single interconnection
  - Daisy chains of 49 and 97 interconnections
  - Compare to theoretical value
  - Electrical connection achieved





## Overview:

- Adaption of 3D flows for advanced technology nodes and automotive applications

## Challenges:

- Process flow divided into different places (ams, CEALETI, BESI and subcon)
- Reliable manufacturing of prototypes

## Highlights:

- Definition of requirements for WL0M and implementation
- Successful fabrication of technology demonstrators



## Overview:

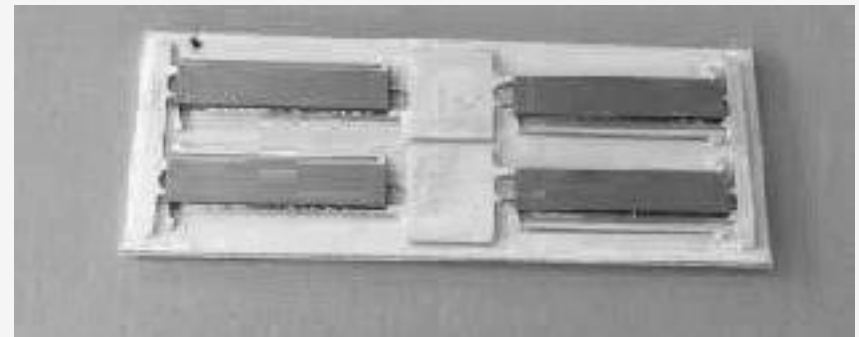
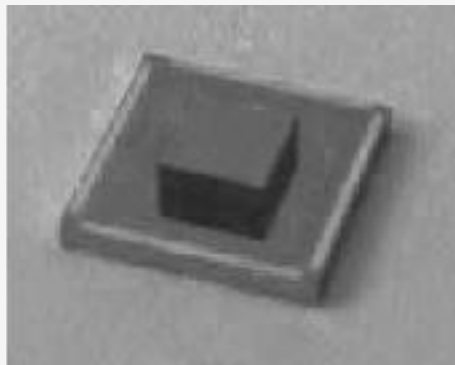
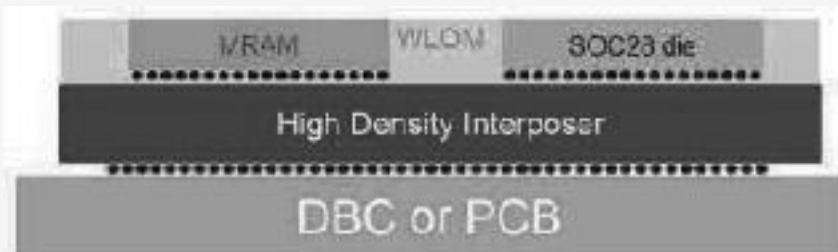
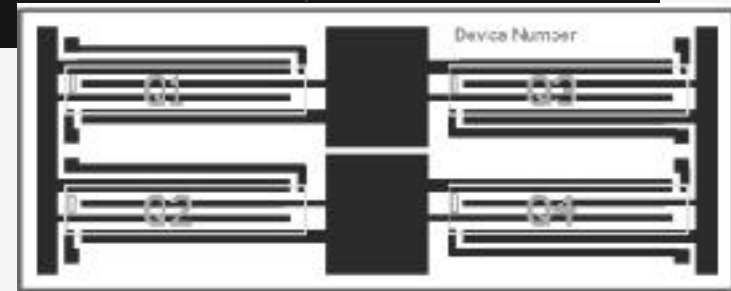
- Assessment of manufacturability of 3D integrated solutions
- Comparison of 3D integrated solution with traditional packaging (cost, form factor, performance)

## Challenges:

- Definition of the final flow
- Evaluation of impact when transferring from R&D to production

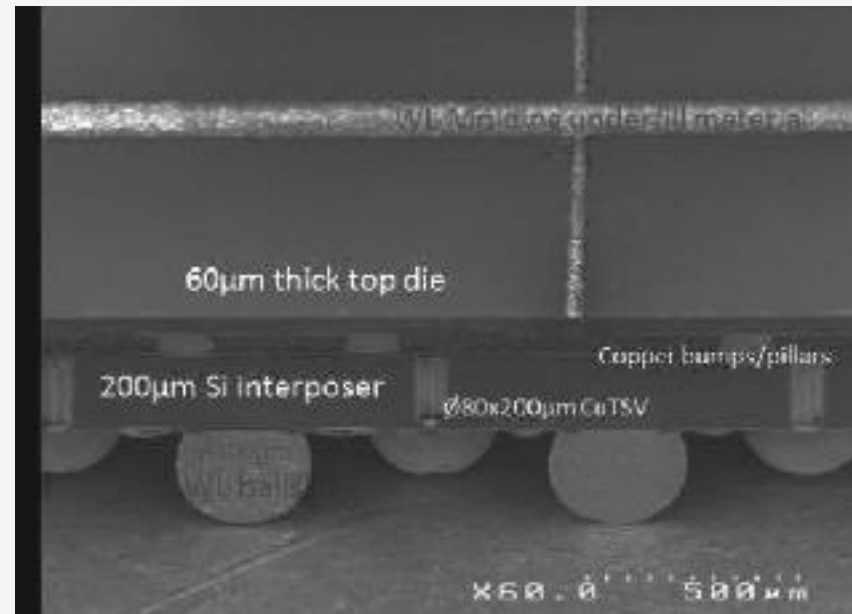
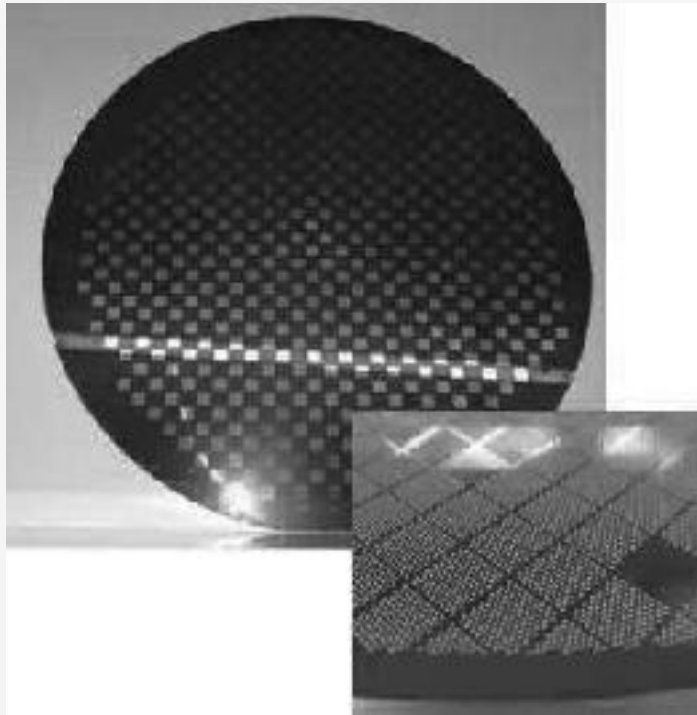
## Highlights:

- 3D integrated solutions (slightly) more expensive but offer significant form factor advantages
- Yield allows for economically feasible production

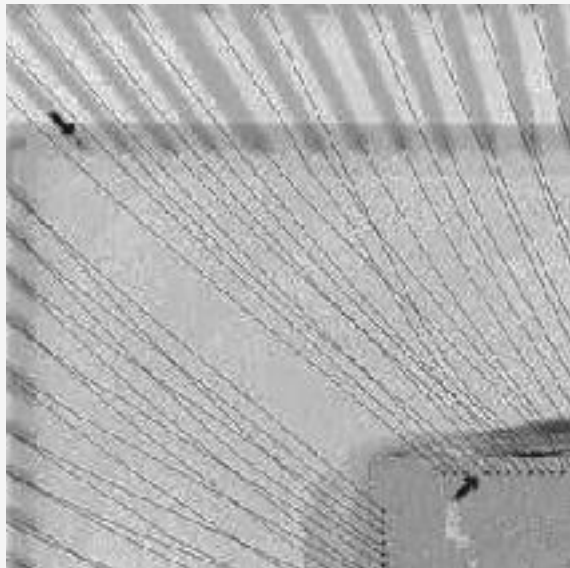
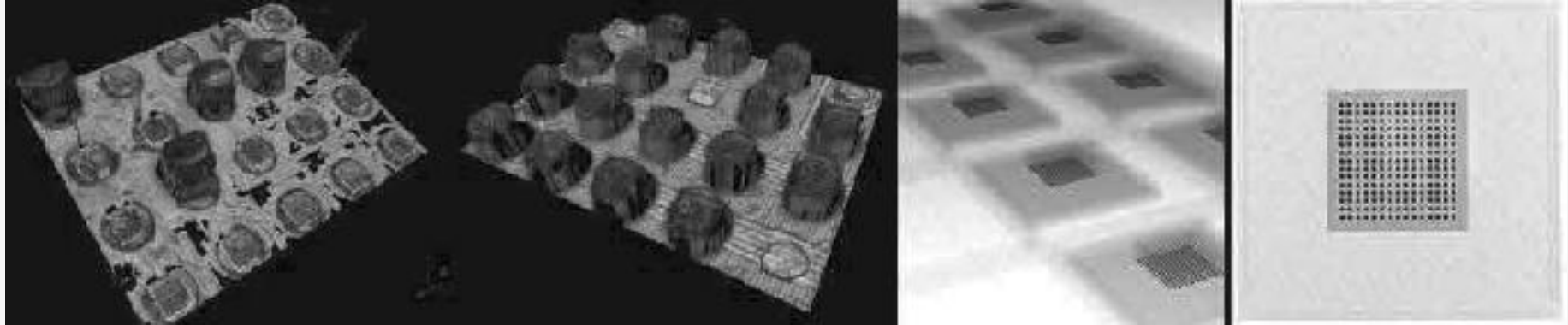


Device	technology	TSV	UBM	Balling	Stacking	WLOM	MRAM
passive HD Interposer	0.35µm 4M	✓	✓	✓ (1 side)	✓	✓	
DCDC	0.35µm HVCMOS						
H-bridge PMOS	0.35µm HVCMOS		✓	✓	✓		
H-bridge NMOS	0.35µm HVCMOS		✓	✓	✓		
Gate Driver	0.18µm HVCMOS		✓	✓	✓		
MRAM	0.18µm HVCMOS						✓
SoC28	28nm CMOS		✓	✓	✓		
Cap - IPD	based on TSV flow	✓					

- Yield losses for wafer processing including 3D steps like TSV are considered both from the study cited in this report as well as from mature manufacturing point of view to be typically in the low %-range.
- System integration of prototypes as demonstrated in ATHENIS\_3D with D2W stacking of high density I/O flip chip interconnects required optimization of the new modules (e.g. D2W, wire bonding on interposer) to bring the yield in 3 iterations from 10% to 60% to deliver a sufficient number of samples for the SoC28 characterization and reliability investigations.



- TSV100/80 in high volume production (medical, consumer)
- Specific needs for ATHENIS\_3D addressed
  - Cu TSV
  - WLOM (TSV → D2W stacking → WLOM → bumping)

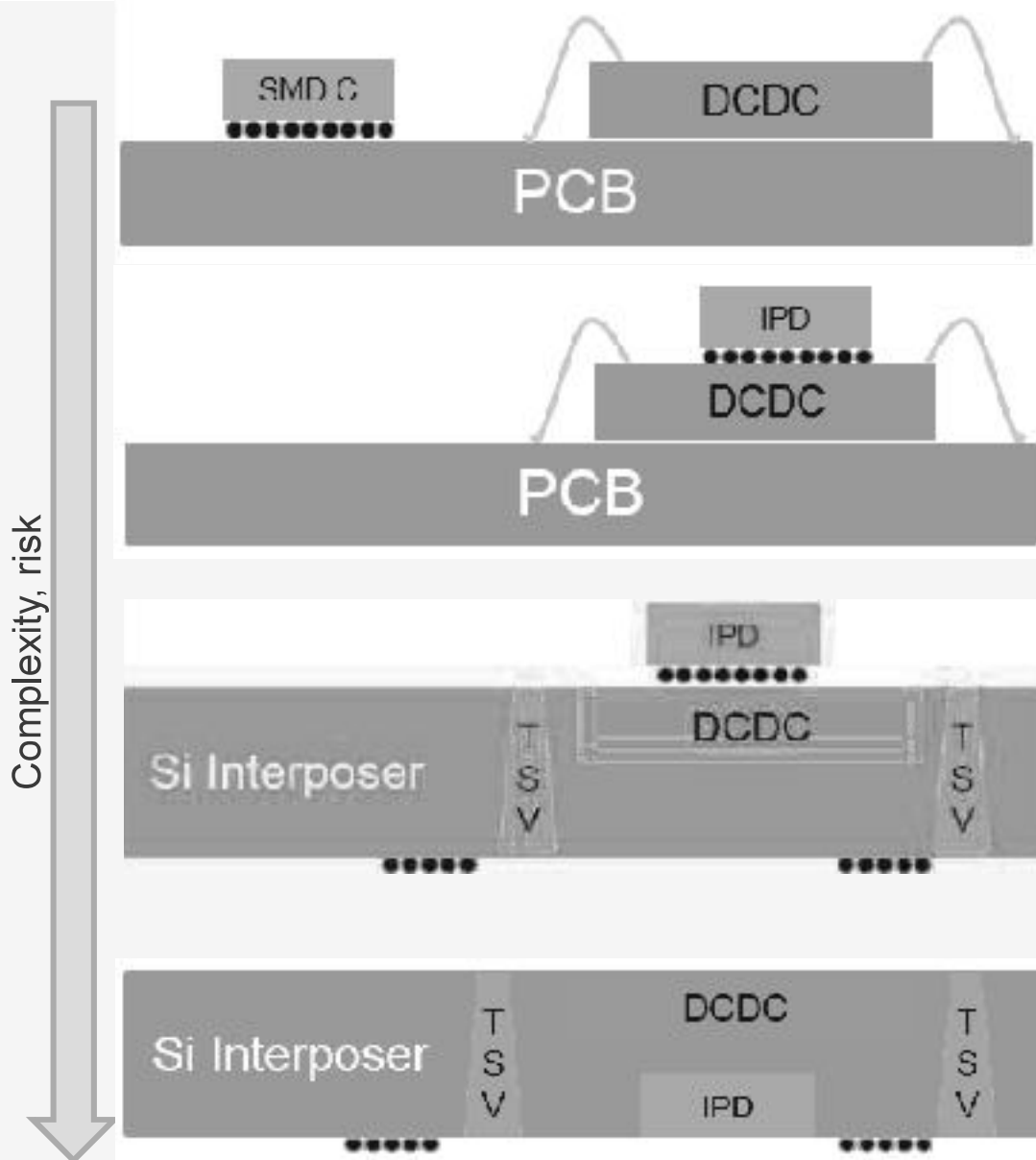


## D2W stacking

- Initial samples mechanically ok but 15% opens (1<sup>st</sup> if each sample placed on substrate w/o bonding)
- Software upgrade to correct issue

## Wire bonding

- Problems at assembly (225 wire bonds to staggered leadframe)
- Additional iteration for improved yield



Overall cost ~ +30%  
 No performance difference  
 Better cooling

Overall cost ~220%  
 Smaller possible form factor (space for additional chips on interposer)

Overall cost ~220%  
 Smallest possible form factor (space for additional chips on interposer)





Standard driver: \$0.762 per unit	==> 4 x drivers:	\$3.128
Industrial MOSFET: \$0.449 per unit	==> 4 x MOSFETS:	\$1.796
<b>Total</b>		<b>\$ 4.924</b>

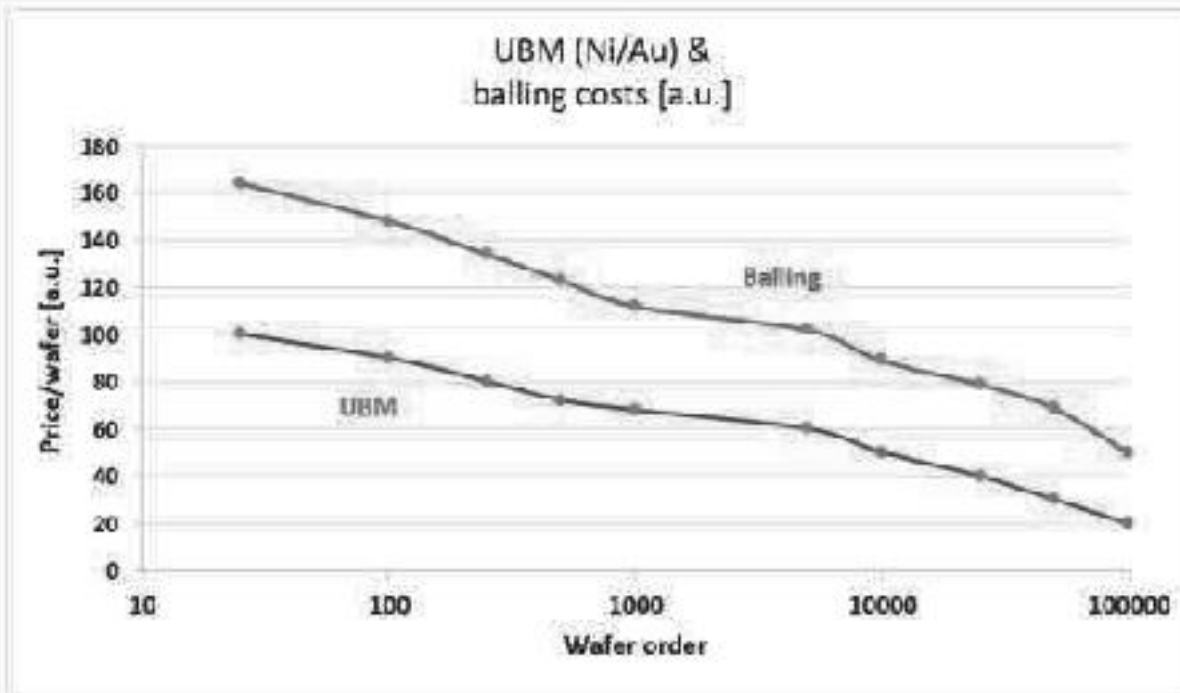
Device	price range	avg. price	total
NMOS 100mOhm	€ 1.00 – 1.20	€ 1.10 x2	€ 2.20
PMOS 100mOhm	€ 1.30 – 1.50	€ 1.40 x2	€ 2.80
Smart Driver	€ 1.80 – 2.00	€ 1.90 x1	€ 1.90
<b>Total</b>			<b>€ 6.90</b>

Area for  $R_{ON} \leq 100\text{mOhm} @ 175^\circ \text{C}$

**Advantages of integrated solution:**

- Integration of a current mirror pad (actual current, voltage and temperature of the transistor)
- Reverse polarity protection (HV transistor concept)
- Advanced VDS loop, current switch control and extended safety functions (integrated driver IC)

# Cost UBM, balling and stacking



- Subcontracted costs: UBM & balling
- Costs strongly dependent on volume
  - Balling costs dominating

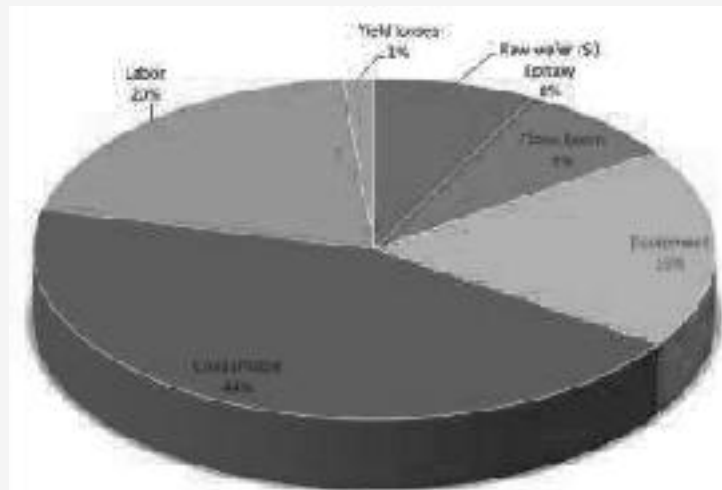
D2W System	CHAMEO advanced	TC advanced
accuracy	3µm	2µm
soldering	Dip fluxing + general reflow	TC local reflow
uph	4500	1000
cost/bond (~€ ct) relative units	1	7x

D2W stacking costs strongly dependent on soldering approach (C2/C4 vs. TCB)

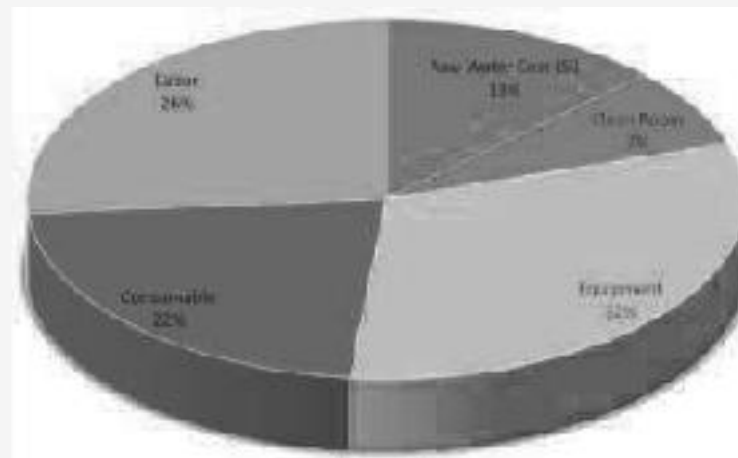
# Cost contribution CMOS and 3D (W TSV)



0.35μm HV CMOS

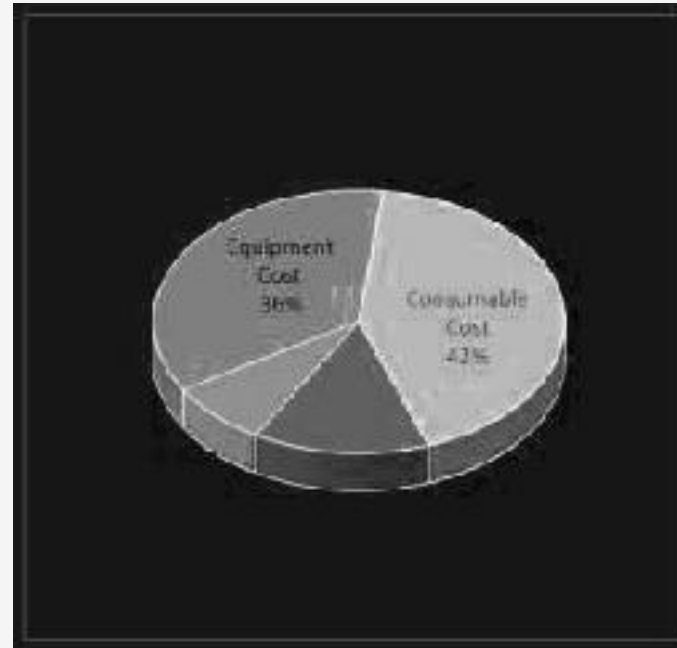
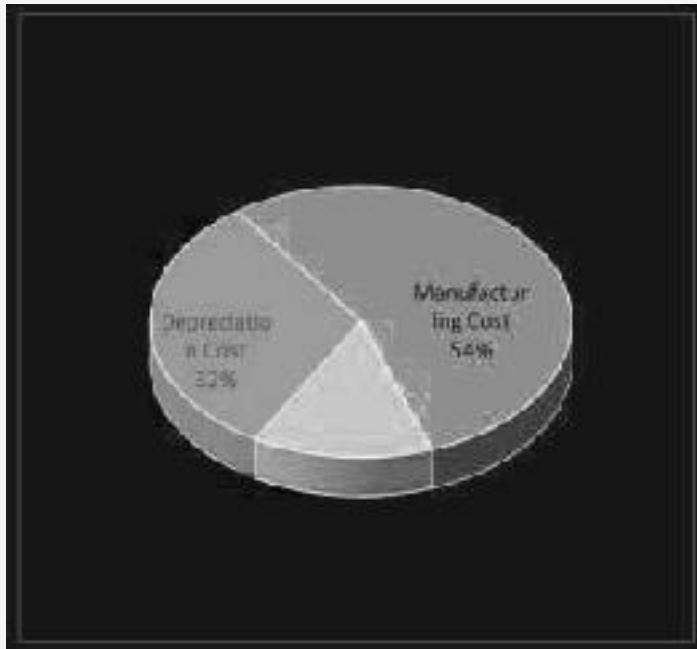


3D module ams (W TSV)



Technology	Wafer cost	TSV / BRDL	UBM	Balling	WLOM	MRAM
0.35μm HV CMOS	100%	75%	13%	23%		
0.18μm HV CMOS	155%	49%	9%	15%		14%
4M HD passive interposer + TSV + BRDL + UBM + WLOM + 1 side balling	169%					

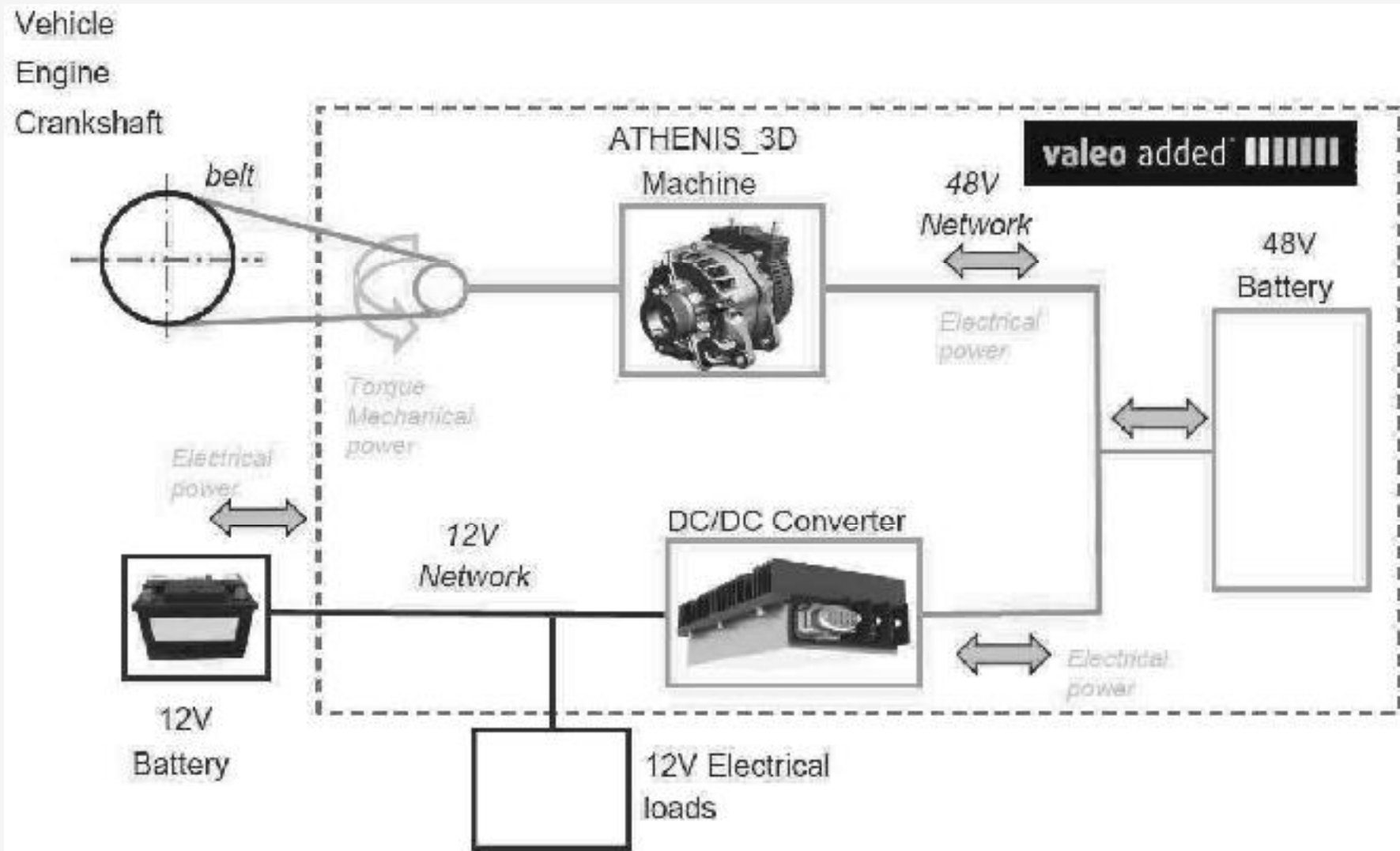
Relative to base technology



Slightly different numbers compared to ams

- Different process
- Not manufacturer

→ potential to process Cu TSVs with improved resistance at same or lower manufacturing costs





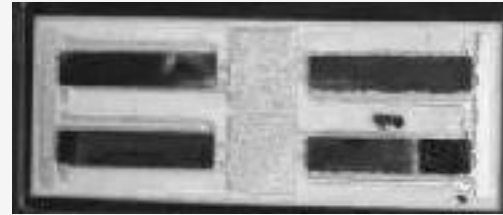
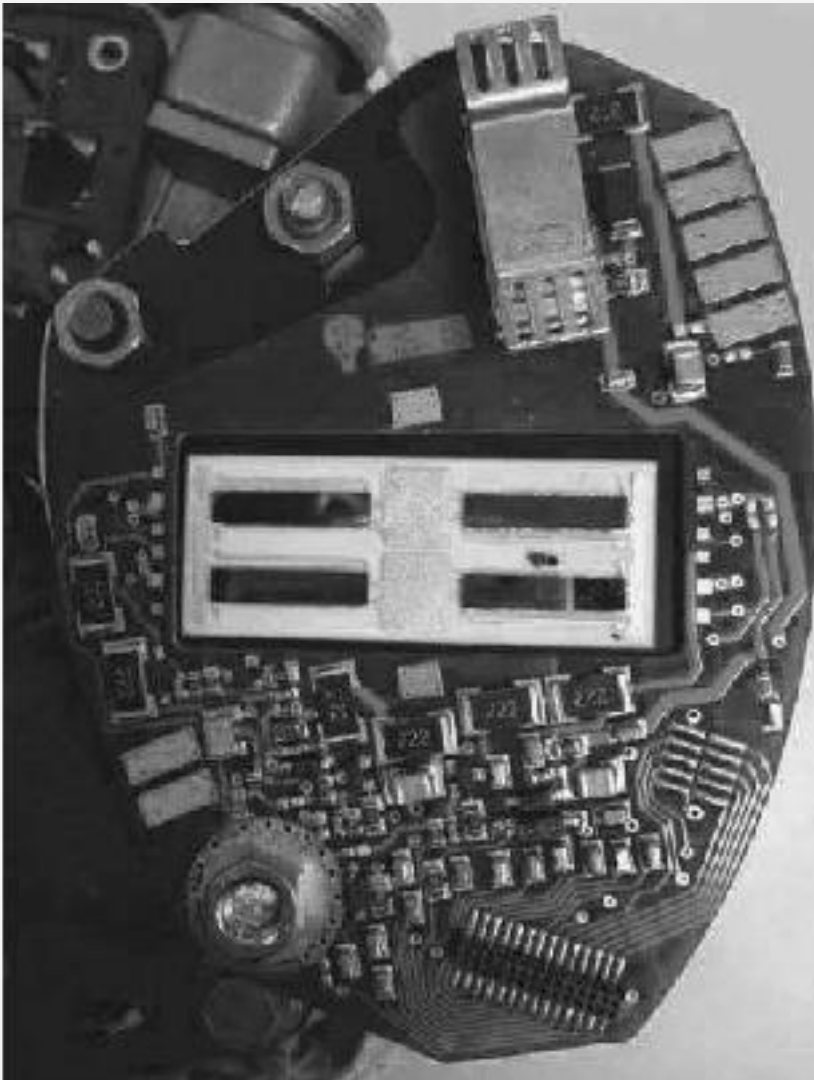
Operating range	
Maximum ambient temperature	80°C
Maximum continuous rotational speed	16,000rpm
Permanent Alternator current on 48V side	0 to 30A
Voltage regulation	54V+/-1V
Maximum rotor current	1.5A

The 48V alternator has been adapted specifically for ATHENIS\_3D demonstrator

# D665: Alternator control module

ATHENIS 3D

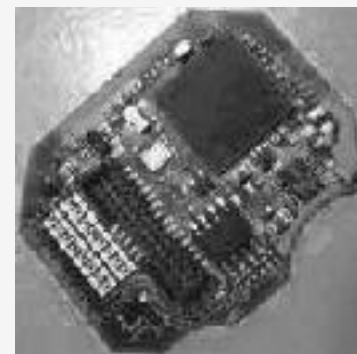
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H-bridge  
(HVCMOS on DBC)



Interface PCB  
(includes drivers for  
H-bridge)



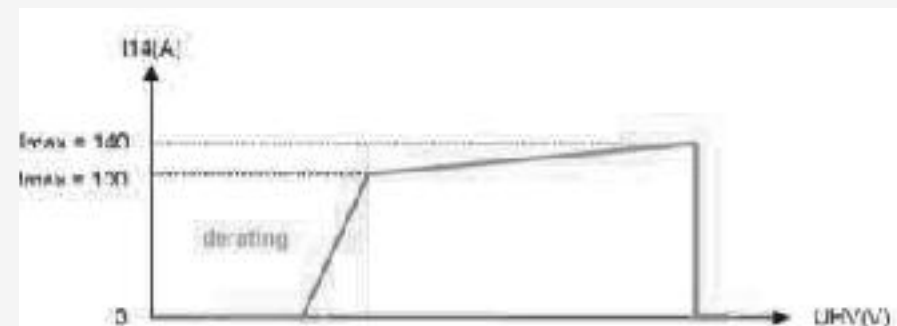
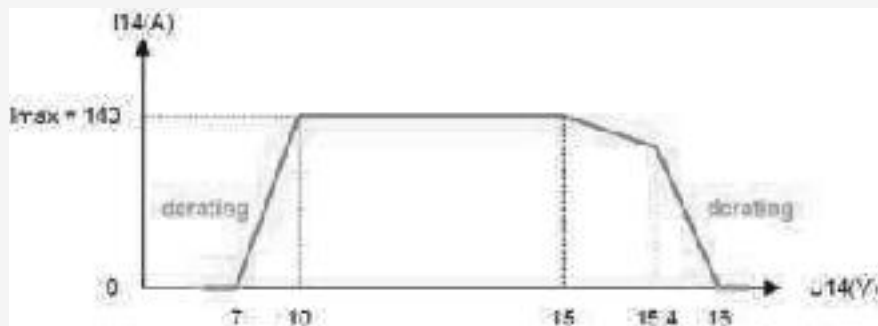
Fast prototyping  
module

# D665: DCDC converter requirements



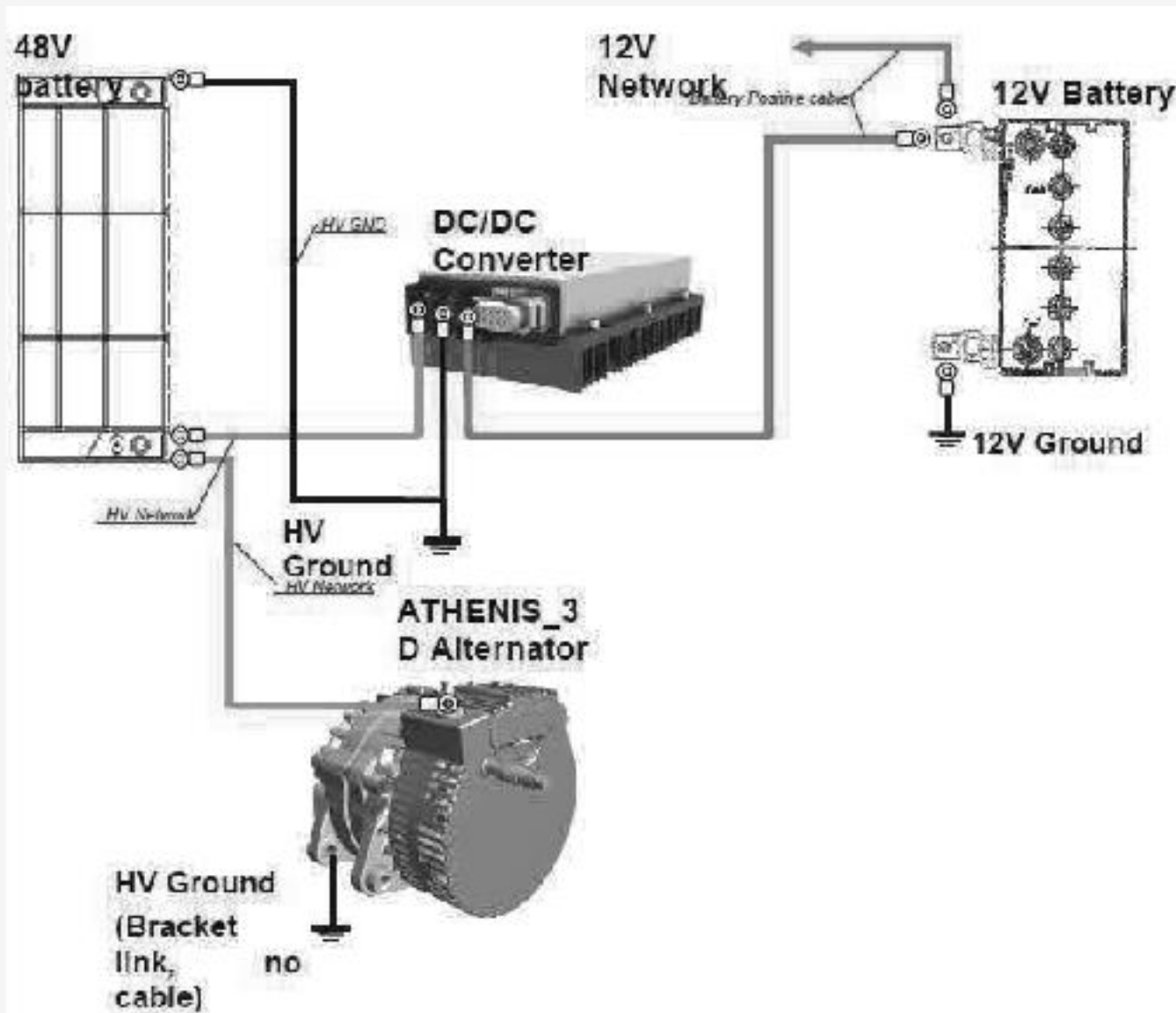
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- output power between  $-30^{\circ}\text{C}$  and  $+70^{\circ}\text{C}$ 
  - : 2.0kW @  $U_{14} = 14\text{V}$
- air cooled
  - : 4 × regulated fans, better with airflow
- efficiency
  - : Efficiency higher than 75% for output power between 10% and 50%
  - Efficiency higher than 85% for output power between 50% and 100%
- power architecture
  - : 4 × 500W power cells in parallel
- control
  - : CAN high-speed (500kbits/s)





# D665: System wiring for prototype



Cranking by conventional starter → all signals measurement

Idle speed regulation at 48V → 48V and 12V voltage measurements

Idle speed regulation at 48V versus loads → 12V and 48V voltage and current measurements

Idle speed regulation at 48V versus switched loads → 12V and 48V voltage and current measurements

48V regulation versus speed/loads/switching → 12V and 48V voltage and current measurements

12V regulation versus 48V variation (large signal) → 48V and 12V voltage measurements

Driving measurements → 12V and 48V voltage and current measurements